

Notice of References Cited		Application/Control No. 10/047,717	Applicant(s)/Patent Under Reexamination KNAPP, RICHARD J.	
		Examiner Tan Dean D. Nguyen	Art Unit 3689	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,862,585	03-2005	Planalp et al.	707/1
*	B	US-6,385,620	05-2002	Kurzius et al.	707/104.1
	C	US-			
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	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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